

<b>Notice of References Cited</b>	Application/Control No. 10/594,852		Applicant(s)/Patent Under Reexamination WEI ET AL.	
	Examiner RICHARD BOWEN		Art Unit 2156	Page 1 of 1

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*	B	US-7,174,343 B2	02-2007	Campos et al.	707/737
*	C	US-7,433,879 B1	10-2008	Sharma et al.	1/1
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.